New Insights and Techniques for Neural Networks

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Message from the Guest Editors

In recent years, there has been a significant increase in the volume, veracity, and variety of machine learning applications. This has led to growing challenges and new possibilities for researchers to effectively extract hidden features in a broad range of scientific and engineering fields. The success of deep learning comes primarily from the availability of algorithms, large data, and computer power. Neural networks in particular have become an essential part of artificial intelligence and machine learning and are applied to a wide range of applications, including medical imaging, computer vision, speech signal processing, robotics, and more. Through the interconnection of nodes and a learning process, neural networks have a unique ability to extract meaning from complex or imprecise data. These networks have the potential to enhance measurements in a diverse range of research fields, and there is a need for in-depth investigations of neural networks-related topics to implement effective, cost-competitive, and practical solutions.

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Special Issue

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Message from the Editor-in-Chief

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